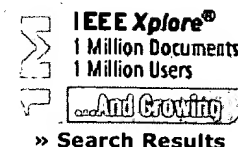


**IEEE Xplore®**
RELEASE 1.8Welcome
United States Patent and Trademark Office[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)**Quick Links****Welcome to IEEE Xplore®**

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

IEEE Enterprise

- ☐ Access the IEEE Enterprise File Cabinet

Your search matched **2** of **1071730** documents.A maximum of **500** results are displayed, **15** to a page, sorted by **Relevance** in **Descending** order.**Refine This Search:**

You may refine your search by editing the current search expression or entering a new one in the text box.

'authoritative pages'

Search☐ Check to search within this result set**Results Key:****JNL** = Journal or Magazine **CNF** = Conference **STD** = Standard**1 Refining Web authoritative resource by frequent structures**

Haofeng Zhou; Yubo Lou; Qingqing Yuan; Ng, W.; Wei Wang; Shi, B.;
Database Engineering and Applications Symposium, 2003. Proceedings. Seventh
International, 16-18 July 2003
Pages:250 - 255

[\[Abstract\]](#) [\[PDF Full-Text \(337 KB\)\]](#) **IEEE CNF****2 A stochastic approach for modeling and computing Web communities**

Greco, G.; Greco, S.; Zumpano, E.;
Web Information Systems Engineering, 2002. WISE 2002. Proceedings of the Third
International Conference on, 12-14 Dec. 2002
Pages:43 - 52

[\[Abstract\]](#) [\[PDF Full-Text \(1400 KB\)\]](#) **IEEE CNF** **Print Format**[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2004 IEEE — All rights reserved